## Last updated 4/14/21

- Static Random Access Memory SRAM
  - Key Attributes
    - Sequential vs. Random Access
    - Read only vs. Read/Write
    - Static s. Dynamic
      Volatile vs. non-Volatile
  - Key Measures
    - Density -
    - Speed +
    - Power
    - Cost / bit -

- SRAM Circuit
  - Memory cell (1 bit) is based on a feedback circuit
  - Bit value is retained as long as power is maintained
  - Fastest read/write (R/W)
  - Highest power
  - Lowest density
  - Used in caches and small data memories



- SRAM Circuit
  - Memory cell (1 bit) is based on a feedback circuit
  - Bit value is retained as long as power is maintained



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- SRAM Write
  - Read Enable (RE) disabled (low)
  - Place BO, B1, B2, B3 on inputs (data in)
  - Apply Address
    - Select the desired word line (high)
    - Select the desired column to input to
  - Strobe write enable bar (WE) low
  - Bit lines override the bit cell inverters and store the new value in the cell

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- Read
  - Write enable bar (WE) high
    - inverters tristated
  - Read Enable (RE) high
  - Apply Address
    - Select the desired word line (high)
    - Select the desired column to output
  - Bit cell inverters drive the bit lines and sense amplifiers read the value







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• SRAM – Timing



- SRAM Complex configuration
  - Array Layout 4Mb, in a x8 (4Mb, x8)
  - No address line sharing



- SRAM Complex configuration
  - Array Layout 4Mb X 8 (4Mx8b) (implicit x1 format)
  - No address line sharing

